

Substitute for form 1449/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/800,111
				Filing Date	March 12, 2004
				First Named Inventor	Mark R. AYRES
				Art Unit	2878
				Examiner Name	K. Wyatt
Sheet	1	of	2	Attorney Docket Number	495812005700

U.S. PATENT DOCUMENTS					
Examiner Initials ¹	Cite No.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS						
Examiner Initials ¹	Cite No.	Foreign Patent Document Country Code ³ -Number-Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁵

Examiner Signature	Date Considered
--------------------	-----------------

¹ EXAMINER: Initial if information considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of the form with next communication to applicant. ² Applicant's unique citation designation number (optional). ³ See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ⁴ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁵ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁶ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁷ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ⁵
	1.	AYRES, M.R. et al. (November 20, 2006). "Scanning Transmission Microscopy Using A Position-Sensitive Detector," <i>Applied Optics</i> 45(33):8410-8418.				
	2.	AYRES, M.R. (2007). "Signal Modulation For Holographic Memories," Doctor of Philosophy Thesis submitted to the Department of Electrical and Computer Engineering, Graduate School of the University of Colorado, 252 pages.				
	3.	FRIEDEN, B.R. (January 1967). "Optical Transfer of the Three-Dimensional Object," <i>Journal of the Optical Society of America</i> 57(1):56-66.				
	4.	KAWATA, Y. et al. (May 10, 1996). "Differential Phase-Contrast Microscope With Split Detector for the Readout System of a Multilayered Optical Memory," <i>Applied Optics</i> 35(14):2466-2470.				
	5.	KOGELNIK, H. (November 1969). "Coupled Wave Theory for Thick Hologram Gratings," <i>The Bell System Technical Journal</i> 48(9):2909-2947.				
	6.	O'BYRNE, J.W. et al. (1999). "Adaptive Optics in Confocal Microscopy," <i>World Scientific</i> , six pages.				
	7.	SHEPPARD, C.J.R. et al. (1977). "Image Formation in the Scanning Microscopes," <i>Optica Acta</i> 24(10):1051-1073.				
	8.	SHEPPARD, C.J.R. et al. (September 1978). "Depth of Field in the Scanning Microscope," <i>Optics Letters</i> 3(3):115-117.				
	9.	SHEPPARD, C.J.R. et al. (September 1989). "Three-Dimensional Imaging in a Microscope," <i>J. Opt. Soc. Am. A</i> 6(9):1260-1269.				
	10.	SHEPPARD, C.J.R. et al. (February 1994). "Three-Dimensional Transfer Functions for High-Aperture Systems," <i>J. Opt. Soc. Am. A</i> 11(2):593-598.				
	11.	STREIBL, N. (February 1985). "Three-Dimensional Imaging by a Microscope," <i>J. Opt. Soc. Am. A</i> 2(2):121-127.				

Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Complete if Known	
				Application Number	10/800,111
				Filing Date	March 12, 2004
				First Named Inventor	Mark R. AYRES
				Art Unit	2878
				Examiner Name	K. Wyatt
				Attorney Docket Number	495812005700
Sheet	2	of	2		

Examiner Signature		Date Considered	
-----------------------	--	--------------------	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.